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O.I.P.E.	PATENT DATE
SCANNED AM QA. A.GT.	

<b>APPLICATION NO.</b> 09/686895	CONT/PRIOR	<b>CLASS</b> 700	SUBCLASS	2121	Wor Buhr
Ø Time Chan		-			

Ting Chen Wen Kuo Yong Liao Chun Lin

Smart automatic recording system and method for monitoring wafer fragmentation  $\dot{}$ 

THE STATE

PTO-2040 12/99

ISSUING CLASSIFICATION							
ORIGIN	AL	CROSS REFERENCE(S)					
CLASS SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONA	L CLASSIFICATION						
			Continued on Issue Slip Inside File Jacket				

TERMINAL	1	DRAWINGS		<b>CLAIMS ALLOWED</b>	
L. DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
☐ The term of this patent				NOTICE OF ALL	OWANCE MAILED
subsequent to (date) has been disclaimed.	(Assistant	Examiner)	(Date)		_
The term of this patent shall					
not extend beyond the expiration date of U.S Patent. No.				ISSUE FEE	
	7	•	No.	Amount Due	Date Paid
	(Primary E	Examiner)	, (Date)		
☐ The terminalmonths of this patent have been disclaimed.				ISSUE BATCH NUMBER	
this patent have been disclaimed.	(Legal Instrume	ants Examiner)	(Date)		
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